



## GN007 Application Note

# Modeling the Thermal Behavior of GaNPX<sup>®</sup> and PDFN packages Using RC Thermal SPICE Models

March 08, 2022

GaN Systems Inc.



- GaN Systems provides RC thermal models allowing customers to perform detailed thermal simulation using SPICE
- Models are created based on FEA thermal simulation and have been verified by GaN Systems
- The Cauer model has been chosen allowing customers to extend the thermal model to their system by including interface material and heat sinks
- The RC thermal models of GaN Systems' devices are available in the datasheets.

- [RC network definition](#)
- [GaN \$PX\$ <sup>®</sup> and PDFN package RC model structure](#)
- [How to use the RC model in a SPICE simulation](#)
- [SPICE simulation examples](#)

## Thermal network

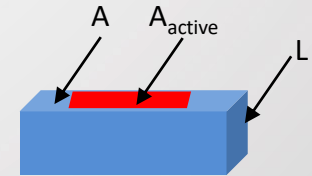
- Thermal resistance ( $R_{\theta}$ )
- Thermal capacitance ( $C_{\theta}$ )
- Time dependent temperature distribution

## Analogy between Electrical and Thermal Parameters

Electrical Parameters	Thermal Parameters
Voltage V (V)	Temperature T (°C)
Current I (A)	Power P (W)
Resistance R ( $\Omega$ )	Thermal resistance $R_{\theta}$ (°C/W)
Capacitance C (F)	Thermal capacitance $C_{\theta}$ (W·s/°C)

## Equations for calculating $R_{\theta}$ and $C_{\theta}$ :

- $R_{\theta} = L/(k \cdot A)$  (1)
- $R_{\theta} = L/(k \cdot A_{\text{active}})$  (2)
- $R_{\theta} = \Delta T/P$  (3)
- $C_{\theta} = C_p \cdot \rho \cdot L \cdot A$  (4)
- $C_{\theta} = C_p \cdot \rho \cdot L \cdot A_{\text{active}}$  (5)



where:

$L$  – layer thickness (m)

$k$  – thermal conductivity (W/m·K)

$A$  – layer area (m<sup>2</sup>)

$A_{\text{active}}$  – device active area (m<sup>2</sup>)

$T$  – temperature (°C)

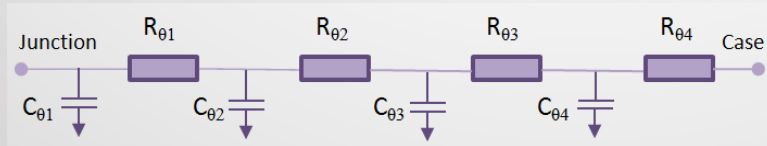
$C_p$  – pressure specific heat capacity (W·s/kg·K)

$\rho$  – density (kg/m<sup>3</sup>)

**Thermal time constant:  $\tau_{\theta} = R_{\theta} \cdot C_{\theta}$**

## Cauer Model

- Cauer RC network is based on the physical property and packaging structure
- The RC elements are assigned to the package layers



### Pros:

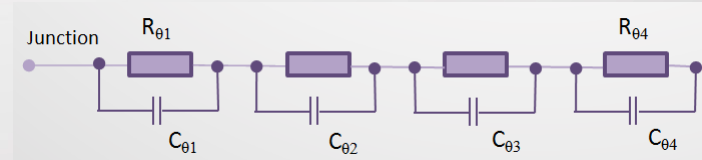
- Cauer RC model reflects the real, physical setup of the device
- Allows to add extra  $R_{\theta}$  and  $C_{\theta}$  to simulate the Thermal Interface Material (TIM) or Heatsink

### Cons:

- Detailed thermal analysis using FEM
- Challenge to extract the thermal capacitance

## Foster Model

- Foster thermal model is not based on the physical property and packaging structure
- $R_{\theta}$  and  $C_{\theta}$  are curve-fitting parameters



### Pros:

- Can be extracted from the datasheet transient response curve
- Can be extracted from a measured heating or cooling curves

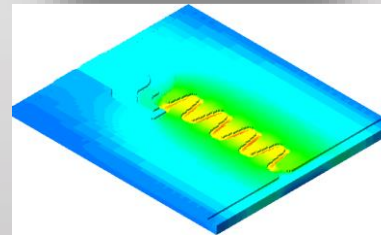
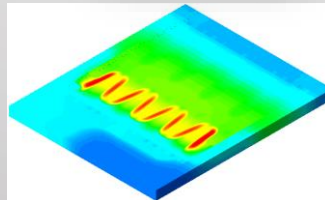
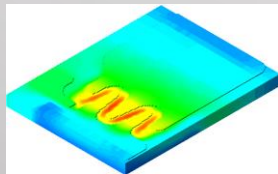
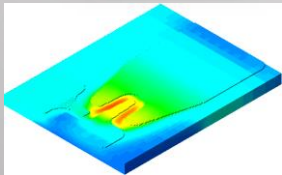
### Cons:

- Valid only for measured conditions
- Adding extra resistance and capacitance requires a new curve fitting

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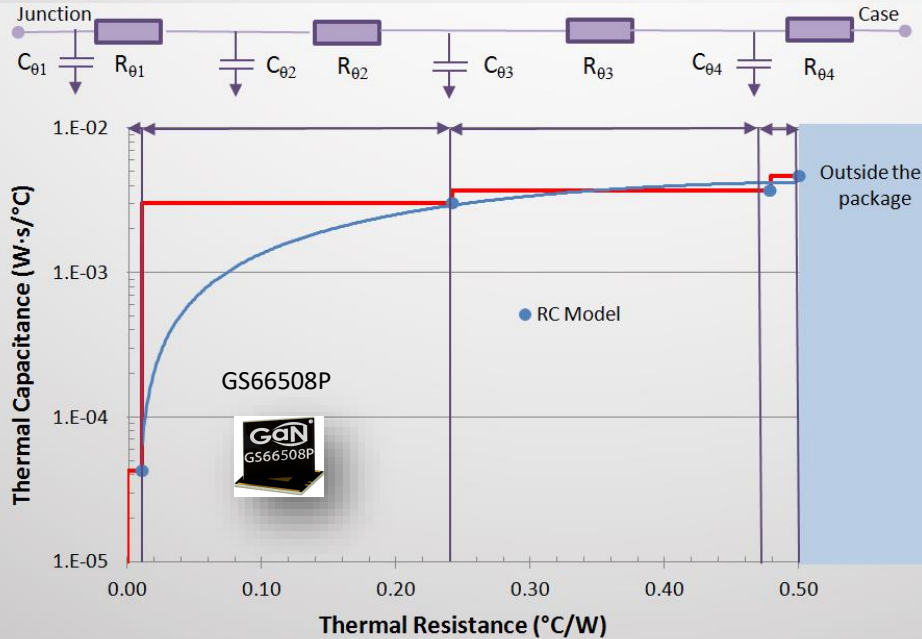
- The detailed steady state and transient thermal analysis were conducted using a 3D heat transfer software with Computational Fluid Dynamics (CFD) capabilities: ElectroFlo and ANSYS Icepack
- During the steady state analysis the device junction-to-case thermal resistance was obtained

## 650 V Devices



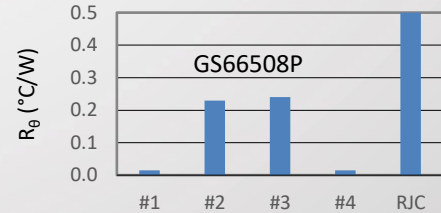
MPN	$R_{\theta JC}$ ( $^{\circ}C/W$ )
GS66502B	2.0
GS66504B	1.0
GS66508B	0.5
GS66508P	0.5

## The Cauer model was chosen for all GaN Systems transistors



The GaN<sup>PX</sup>® package consists of 4 layers:

#1	GaN
#2	Si
#3	Attachment
#4	Cu Base



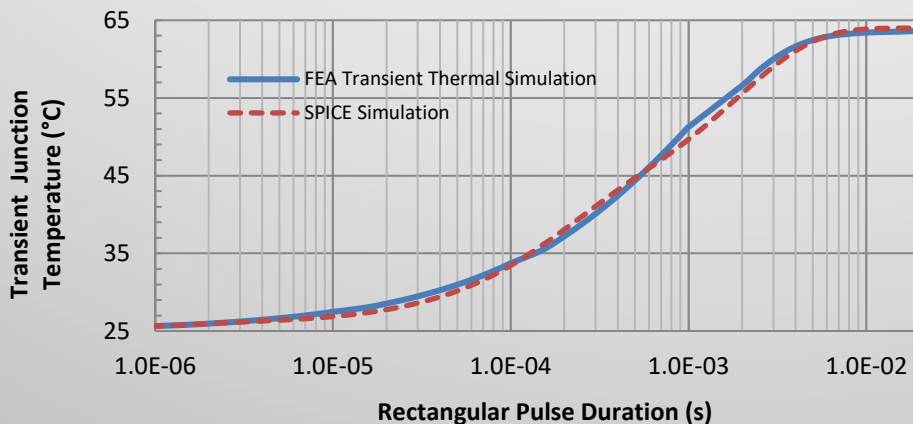
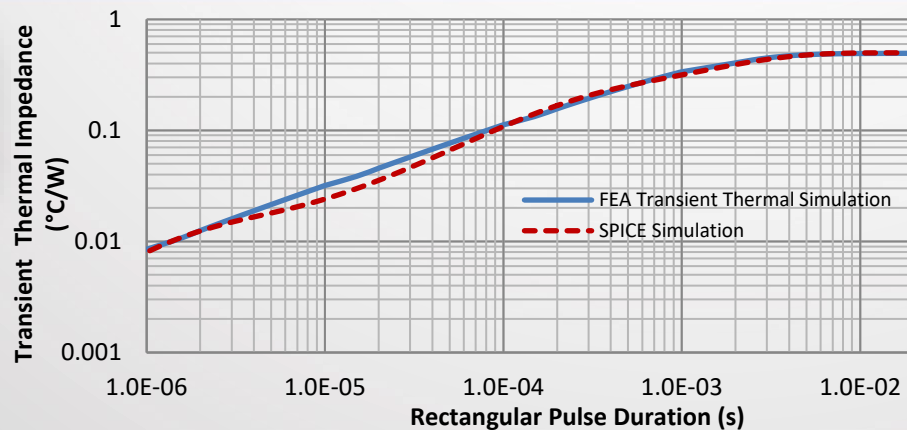
- Layer thermal resistance was derived from the thermal simulation and calculated using the equation (3):

$$R_{\theta 1} = \Delta T / P = (T_J - T_1) / P$$

- Layer thermal capacitance was calculated using the active area of the device (equation (5)):

$$C_{\theta 1} = C_{P1} \cdot \rho_1 \cdot L_1 \cdot A_{\text{active}}$$



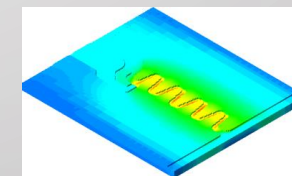
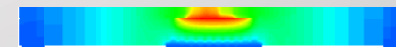
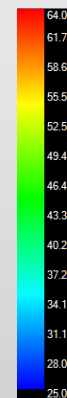


## GS66508P Cauer RC model

	$R_{\theta}$ ( $^{\circ}\text{C}/\text{W}$ )	$C_{\theta}$ ( $\text{W}\cdot\text{s}/^{\circ}\text{C}$ )
#1	0.015	8.0E-05
#2	0.23	7.4E-04
#3	0.24	6.5E-03
#4	0.015	2.0E-03

## Boundary Condition:

- Power  $P = 78\text{ W}$
- $T_{\text{case}} = 25\text{ }^{\circ}\text{C}$



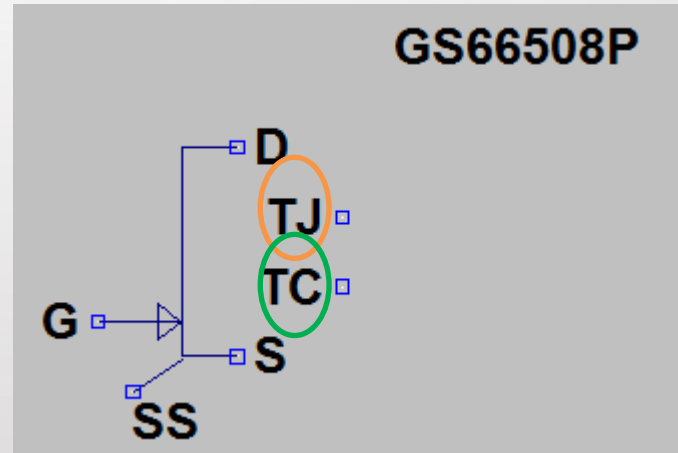
Good agreement between transient thermal simulation and SPICE simulation has been achieved

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- ❑ [SPICE simulation examples](#)

## SPICE Netlist in .lib File :

```
Rth_1 T11 TJ {0.011}  
Cth_1 0 TJ {4.25e-5}  
Rth_2 T22 T11 {0.231}  
Cth_2 0 T11 {2.96e-3}  
Rth_3 T33 T22 {0.237}  
Cth_3 0 T22 {6.65e-4}  
Rth_4 TC T33 {0.021}  
Cth_4 0 T33 {1.01e-3}
```

## SPICE Symbol:



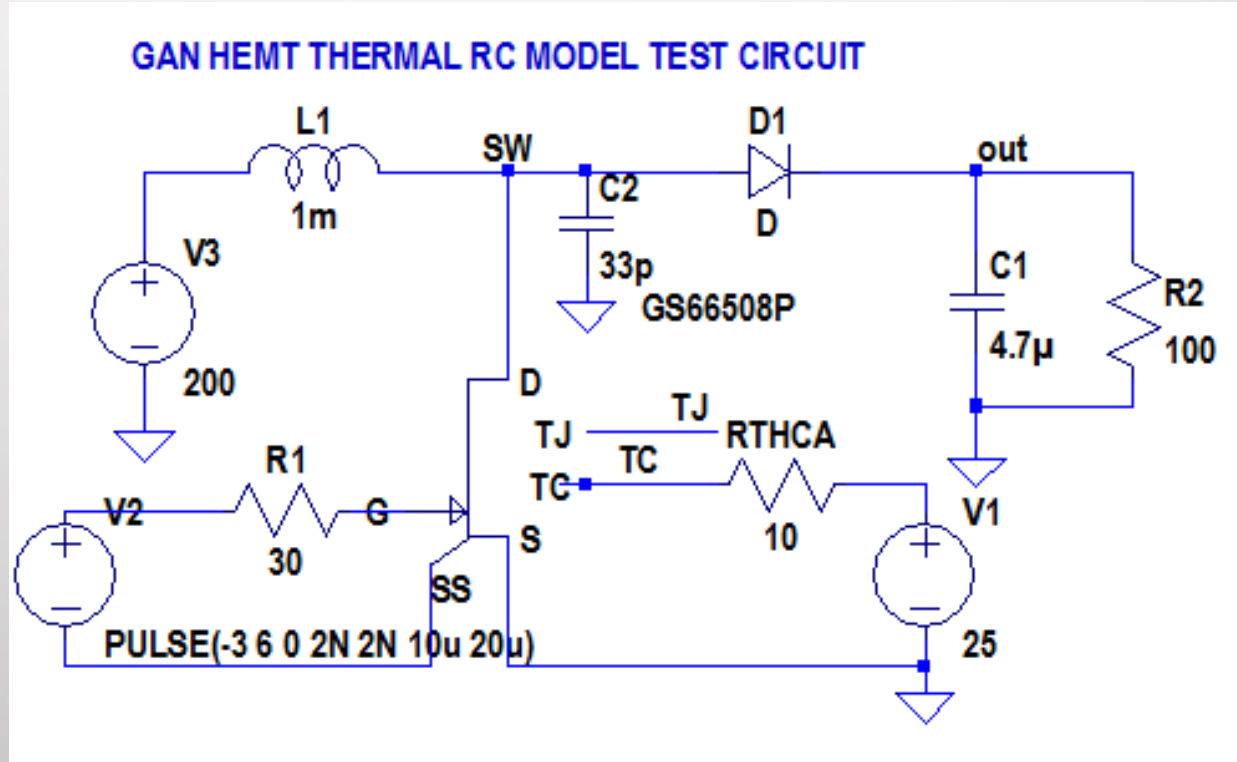
## In the SPICE Schematics:

- Connect  $T_C$  to a voltage equal to the case temperature
- Read  $V(T_J)$  to measure the junction temperature

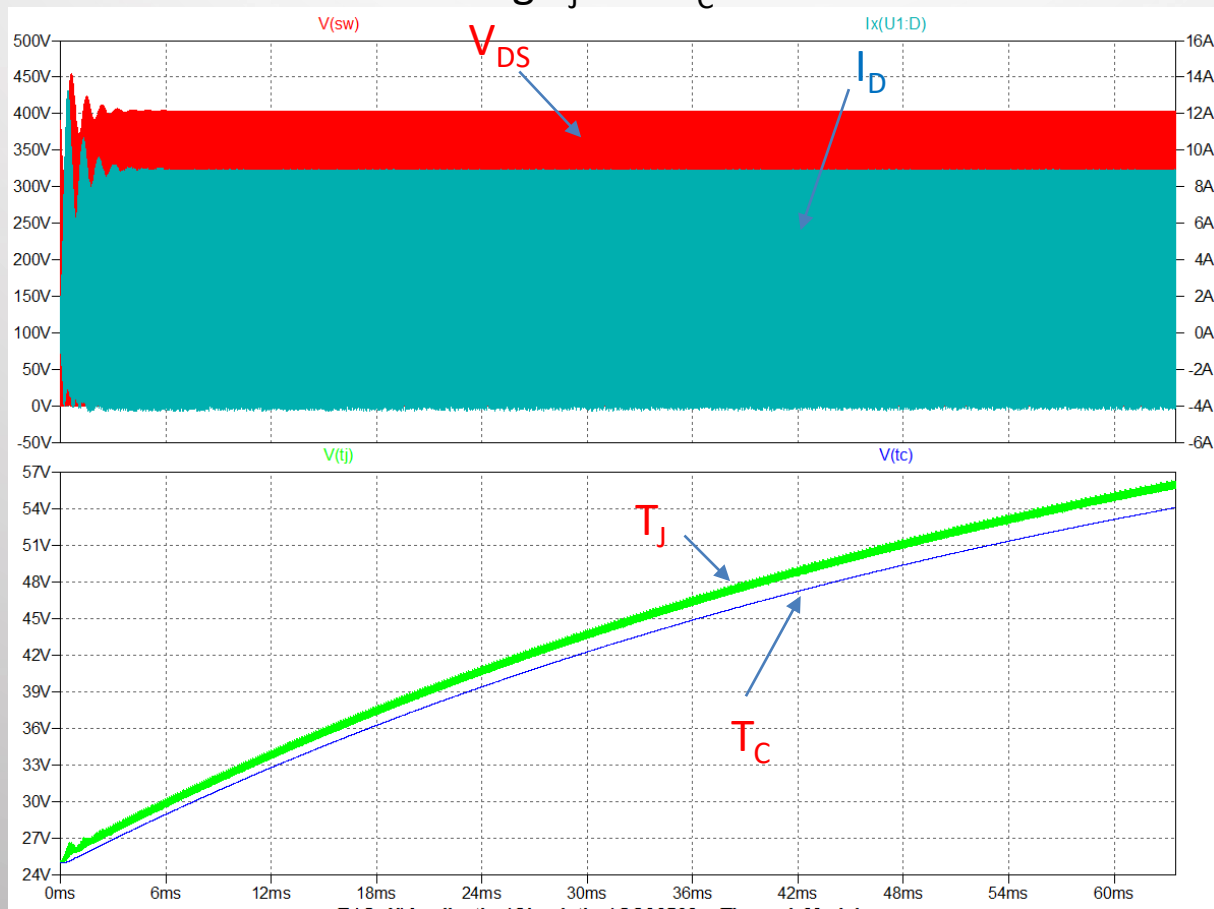
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A simple boost converter circuit was used to verify the functionality of RC thermal model

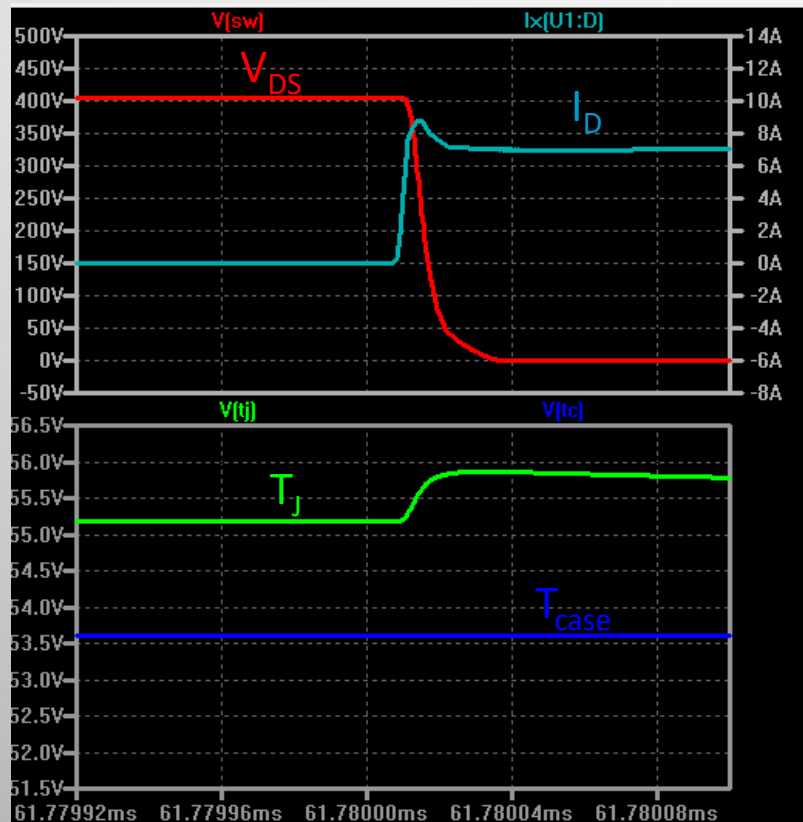
- 200 - 400 V,  $I_{out} = 4$  A
- $D = 0.5$ ,  $F_{sw} = 50$  kHz
- $T_A = 25$  °C
- $R_{THCA} = 10$  °C/W
- Monitor  $T_J$ ,  $T_C$



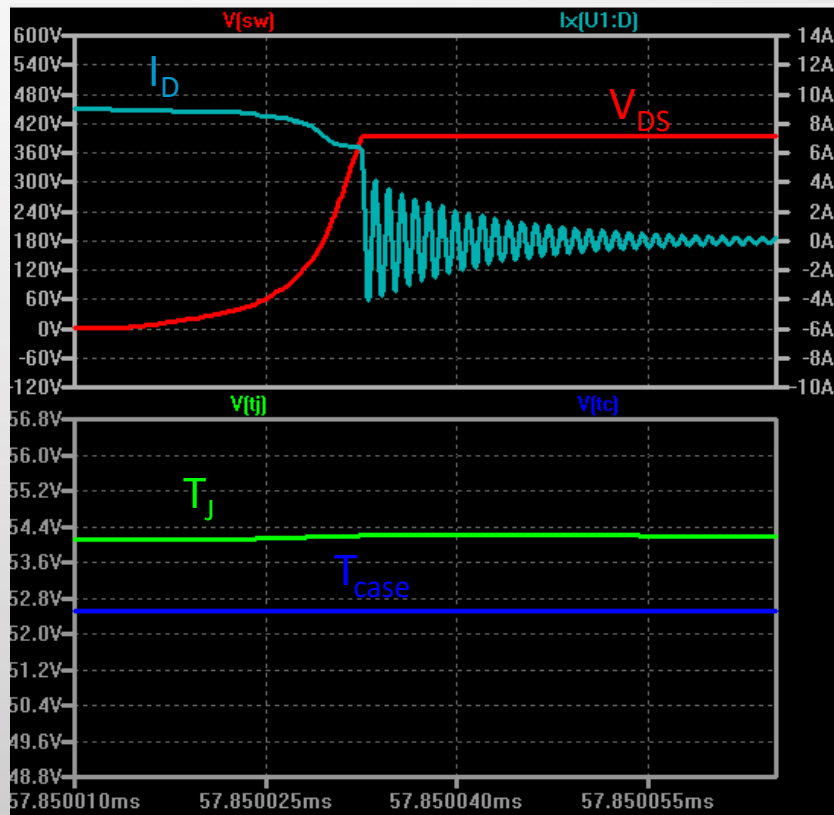
Transient thermal simulation showing  $T_J$  and  $T_C$  time constant for first 70ms



## Thermal simulation – Turn-on



## Thermal simulation – Turn-off





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